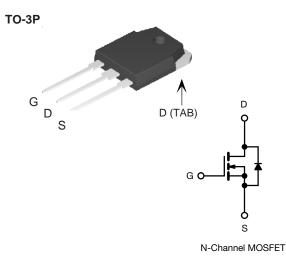


N-Channel 600 V (D-S) Super Junction MOSFET

PRODUCT SUMMARY						
V _{DS} (V) at T _J max.	600					
R _{DS(on)} (Ω) at 25 °C	$V_{GS} = 10 V$	0.19				
Q _g max. (nC)	106					
Q _{gs} (nC)	14					
Q _{gd} (nC)	33					
Configuration	Single					



FEATURES

- Reduced t_{rr}, Q_{rr}, and I_{RRM}
- Low figure-of-merit (FOM) Ron x Qg
- Low input capacitance (Ciss)
- Low switching losses due to reduced Q_{rr}
- Ultra low gate charge (Q_q)
- Avalanche energy rated (UIS)

APPLICATIONS

- Telecommunications
- Server and telecom power supplies
- Lighting
 - High-intensity discharge (HID)
 - Fluorescent ballast lighting
- Consumer and computing - ATX power supplies
- Industrial
 - Welding
 - Battery chargers
- Renewable energy
- Solar (PV inverters)
- Switch mode power supplies (SMPS)

ABSOLUTE MAXIMUM RATINGS ($T_c = 25 \text{ °C}$, unless otherwise noted)									
PARAMETER			LIMIT	UNIT					
Drain-Source Voltage			600	v					
Gate-Source Voltage				v					
V + 10 V	T _C = 25 °C	- I _D -	20						
V _{GS} at 10 V	T _C = 100 °C		13	А					
Pulsed Drain Current ^a			53						
Linear Derating Factor			1.7	W/°C					
Single Pulse Avalanche Energy b			367	mJ					
Maximum Power Dissipation				W					
Operating Junction and Storage Temperature Range			-55 to +150	°C					
T _J = 125 °C			37						
Reverse Diode dV/dt ^d			31	V/ns					
for 10 s			300	°C					
	V _{GS} at 10 V e T_J = [−]	$V_{GS} \text{ at } 10 \text{ V} \frac{T_{C} = 25 \text{ °C}}{T_{C} = 100 \text{ °C}}$ e $T_{J} = 125 \text{ °C}$	$\begin{tabular}{ c c c c c } & SYMBOL & & & & & & & & & & & & & & & & & & &$	$\begin{tabular}{ c c c c c c } \hline $SYMBOL$ $LIMIT$ \\ V_{DS} & 600 \\ V_{GS} & \pm30$ \\ \hline $T_C = 100\ ^{\circ}C$ & I_D & 200 \\ \hline $T_C = 100\ ^{\circ}C$ & I_D & 53 \\ \hline I_T & 1.7 \\ \hline I_T & 1.7 \\ \hline I_S & 1.7 \\ \hline I_T & $$					

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature. b. $V_{DD} = 50$ V, starting T_J = 25 °C, L = 28.2 mH, R_g = 25 Ω , I_{AS} = 5.1 A.

c. 1.6 mm from case.

d. $I_{SD} \leq I_D$, dl/dt = 100 A/µs, starting T_J = 25 °C.



THERMAL RESISTANCE RAT	INGS							
PARAMETER	SYMBOL	TYP. MAX.			UNIT			
Maximum Junction-to-Ambient	R _{thJA}	- 62				°0.00		
Maximum Junction-to-Case (Drain)	R _{thJC}	- 0.5				°C/W		
SPECIFICATIONS (T _J = 25 °C, u	unless otherwi	ise noted)						
PARAMETER	SYMBOL	TES	T CONDIT	IONS	MIN.	TYP.	MAX.	UNIT
Static					1		1	I
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} :	= 0 V, I _D =	250 µA	600	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	e to 25 °C,	I _D = 1 mA	-	0.67	-	V/°C
Gate-Source Threshold Voltage (N)	V _{GS(th)}	V _{DS} =	= V _{GS} , I _D =	250 µA	2	-	4	V
Cata Source Laskage		$V_{GS} = \pm 20 V$ $V_{GS} = \pm 30 V$		-	-	± 100	nA	
Gate-Source Leakage	I _{GSS}			-	-	± 1	μA	
Zara Gata Valtaga Drain Current	la a a	V _{DS} =	= 520 V, V _C	_{as} = 0 V	-	-	1	μA
Zero Gate Voltage Drain Current	IDSS	V _{DS} = 520 \	/, V _{GS} = 0 '	V, T _J = 125 °C	-	-	500	
Drain-Source On-State Resistance	R _{DS(on)}	$V_{GS} = 10 V$		_D = 11 A	-	0.19	-	Ω
Forward Transconductance	9 _{fs}	V _{DS}	= 30 V, I _D	= 11 A	-	7.0	-	S
Dynamic								-
Input Capacitance	C _{iss}		V _{GS} = 0 V,		-	2322	-	
Output Capacitance	C _{oss}	$V_{DS} = 100 V,$ f = 1 MHz		-	105	-	pF	
Reverse Transfer Capacitance	C _{rss}			-	4	-		
Effective Output Capacitance, Energy Related ^a	C _{o(er)}	V_{DS} = 0 V to 520 V, V_{GS} = 0 V		-	84	-		
Effective Output Capacitance, Time Related ^b	C _{o(tr)}			-	293	-		
Total Gate Charge	Qg	V _{GS} = 10 V I _D = 11 A,		A, V _{DS} = 520 V	-	71	106	nC
Gate-Source Charge	Q _{gs}				-	14	-	
Gate-Drain Charge	Q _{gd}				-	33	-	
Turn-On Delay Time	t _{d(on)}				-	22	44	
Rise Time	t _r		V_{DD} = 520 V, I_D = 11 A, V_{GS} = 10 V, R_g = 9.1 Ω		-	34	68	ns
Turn-Off Delay Time	t _{d(off)}	V _{GS} =			-	68	102	
Fall Time	t _f			-	42	84		
Gate Input Resistance	Rg	f = 1 MHz, open drain		-	0.78	-	Ω	
Drain-Source Body Diode Characterist	cs							
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the		-	-	21	- A	
Pulsed Diode Forward Current	I _{SM}	p - n junction diode			-	-		53
Diode Forward Voltage	V _{SD}	T _J = 25 °C, I _S = 11 A, V _{GS} = 0 V		-	0.9	1.2	V	
Reverse Recovery Time	t _{rr}	$T_J = 25 \text{ °C}, I_F = I_S = 11 \text{ A},$ dl/dt = 100 A/µs, V _R = 25 V		-	160	-	ns	
Reverse Recovery Charge	Q _{rr}			-	1.2	-	μC	
Reverse Recovery Current	I _{RRM}			-	14	-	A	

Notes

a. $C_{oss(er)}$ is a fixed capacitance that gives the same energy as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} . b. $C_{oss(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} .



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

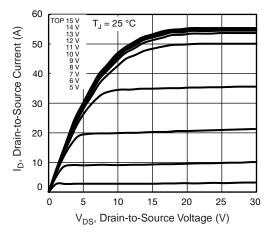


Fig. 1 - Typical Output Characteristics

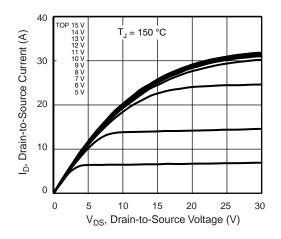


Fig. 2 - Typical Output Characteristics

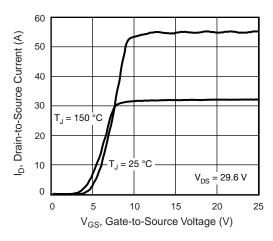


Fig. 3 - Typical Transfer Characteristics

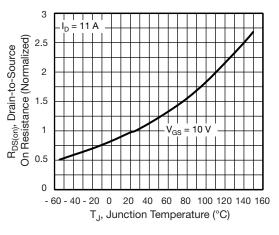


Fig. 4 - Normalized On-Resistance vs. Temperature

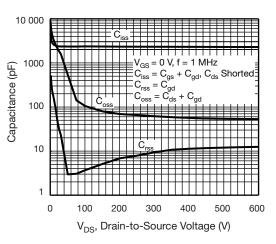


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

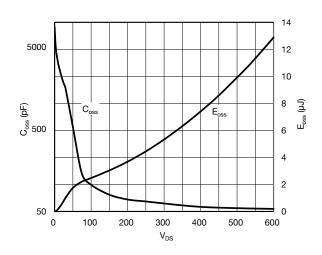


Fig. 6 - C_{oss} and E_{oss} vs. V_{DS}

VBPB16R20S



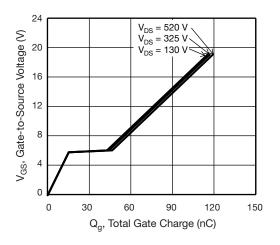


Fig. 7 - Typical Gate Charge vs. Gate-to-Source Voltage

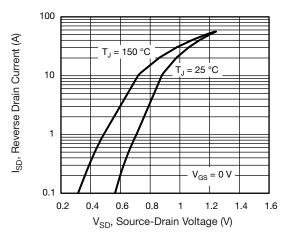


Fig. 8 - Typical Source-Drain Diode Forward Voltage

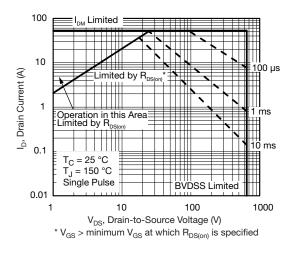


Fig. 9 - Maximum Safe Operating Area

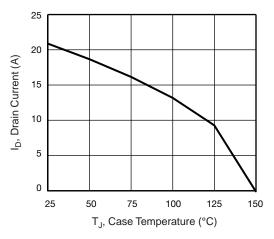


Fig. 10 - Maximum Drain Current vs. Case Temperature



Fig. 11 - Temperature vs. Drain-to-Source Voltage



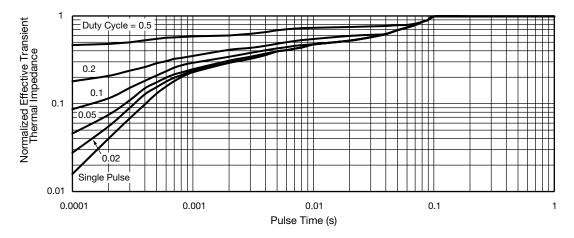


Fig. 12 - Normalized Thermal Transient Impedance, Junction-to-Case

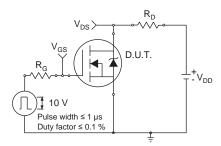


Fig. 13 - Switching Time Test Circuit

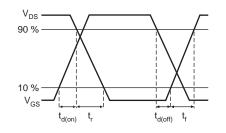


Fig. 14 - Switching Time Waveforms

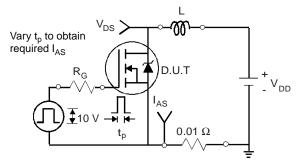


Fig. 15 - Unclamped Inductive Test Circuit

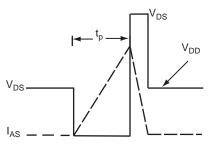


Fig. 16 - Unclamped Inductive Waveforms

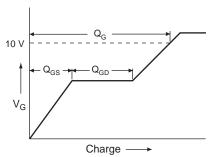
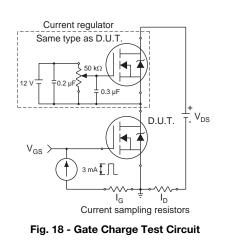
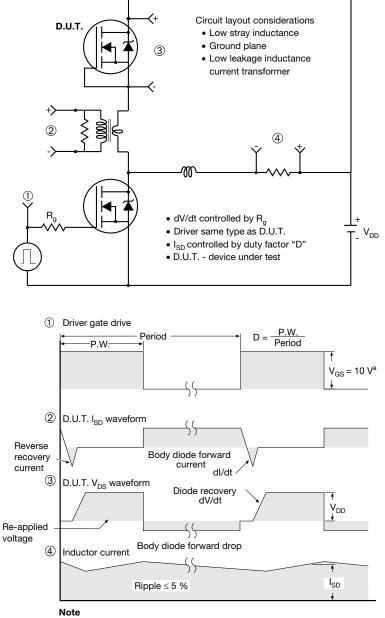


Fig. 17 - Basic Gate Charge Waveform





Peak Diode Recovery dV/dt Test Circuit



a. $V_{GS} = 5$ V for logic level devices

Fig. 19 - For N-Channel



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